

Shenzhen Pancun Technology Co.,Ltd.

Industrial CFast

PCCSXXXGT48WT6

Product DataSheet

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9.	Barcode Description	错误！未定义书签。
10.	Partnumber Decoder	错误！未定义书签。

Revision History

Revision	Draft Date	History	Author
1.0	2021/6/2	New release	Richard Chen
1.1	2021/6/16	● Added 1TB information ● Revise TBW/DWPD information ● Revise power consumption information	Richard Chen
1.2	2022/1/26	Added Write Protect function support	Richard Chen
1.3	2022/1/28	Removed safety certification	Richard Chen
1.4	2022/6/22	Added Extend grade: -25°C ~ 85°C series	Richard Chen

Product Overview

● Capacity ▪ TLC: 64GB up to 1TB ▪ pSLC: 32GB up to 128GB ● SATA Interface ▪ SATA Revision 3.2 ▪ SATA Gen3/Gen2/Gen1 interface ● Performance ▪ Read up to 550 MB/s ▪ Write up to 500 MB/s ● Power Consumption^{Note1} ▪ Active mode: < 1,400 mW ▪ Idle mode: <180 mW ● Reliability^{Note2} ▪ MTBF > 3,000,000 hours ▪ UBER < 1 sector per 10¹⁶ bits ▪ TBW^{Note3}: ➢ TLC: up to 1,080 TB ➢ pSLC: up to 6,400 TB ● Low Power Management ▪ DEVSLP Mode (Optional) ● ECC ▪ LDPC / RAID ECC ▪ Low density parity check code (>120bit/KBytes)	● Temperature Range^{Note4} ▪ Operation Temperature: ➢ Standard grade: 0°C ~ 70°C ➢ Wide grade: -40°C ~ 85°C ➢ Extend grade: -25°C ~ 85°C ▪ Storage Temperature: ➢ -40°C ~ 85°C ● RoHS Compliant ● EMI Compliant ▪ EN55032, CISPR 32 (CE) ▪ ANSI C63.4 (FCC) ▪ CNS 13438 (BSMI) ▪ VCCI-CISPR 32 (VCCI) ● Special Features & Flash Management ▪ Advanced Wear Leveling ▪ Bad Block Management ▪ TRIM ▪ SMART ▪ Over-Provision ▪ SmartZIP™
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Notes:

1. Please refer to “4.2 Power Consumption” for details.
2. Please refer to “Environmental Specifications” in chapter 3 for details.
3. Please refer to “2.4 TBW & DWPD” for details.
4. The operation temperature means the case temperature (T_c), in which can be detected via the SMART.

1. INTRODUCTION

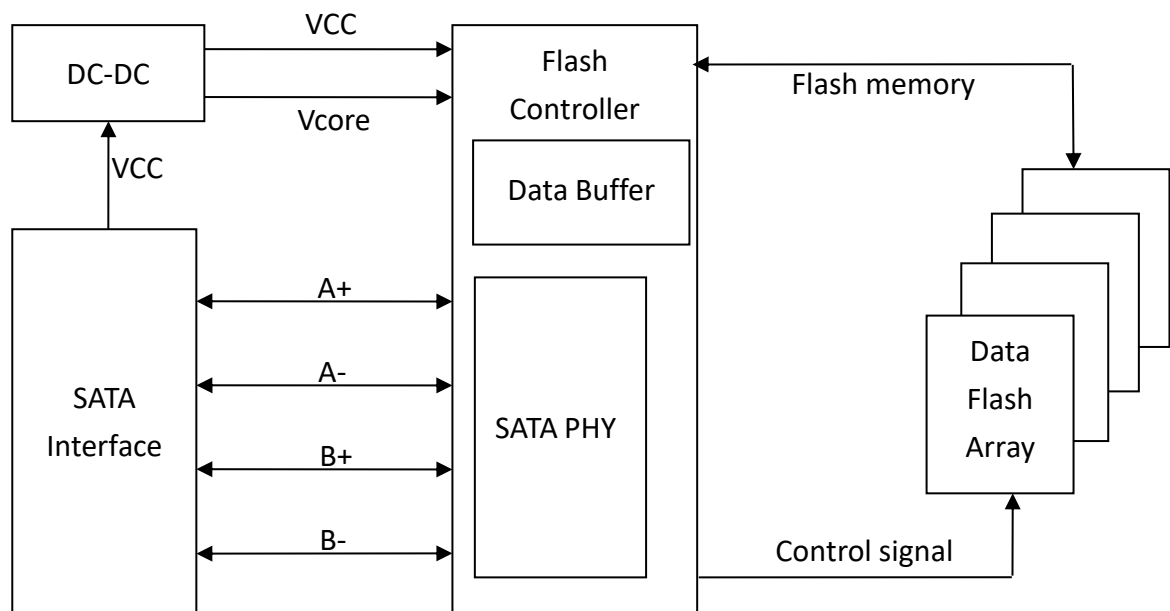


1.1. General Description

Pancun's CFast delivers all the advantages of Flash Disk technology with the Serial ATA III interface and is fully compliant with the standard CFast form factor. Given the features of the low power consumption, small form factor, and high shock-resistance, CFast is an attractive solution to replace the conventional [PATA-interfaced] CompactFlash card in industrial applications or markets where performance is a major concern.

CFast, consisting of a SATA-based 7-pin standard interface for data segment and 17-pin for power and controller segment, it can reach up to 550MB/s read and 500MB/s write high performance standard.

1.2. Block Diagram



CFast Block Diagram

2. PRODUCT SPECIFICATIONS



2.1. Product Specifications

- **Capacity**
 - TLC: From 64GB up to 1TB
 - pSLC: From 32GB up to 128GB
- **Electrical/Physical Interface**
 - SATA Interface
 - Compatible with SATA 1.5Gbps, 3Gbps and 6Gbps interface
 - AC coupling for transmitter and receiver
 - Self-calibrated and embedded termination resistor at transmitter
 - Support expanded register for SATA protocol 48 bits addressing mode
 - Support power management
- **Supported NAND Flash**
 - Kioxia BiCS5 3D-TLC, Toggle 3.0
- **ECC Scheme**
 - Applies the LDPC (Low Density Parity Check) of ECC algorithm
- **Operation Voltage Supply**
 - 3.3V ± 5%
- **Power Saving Implementation**
 - Idle mode
 - Partial mode
 - Slumber mode
- **LBA Range**
 - IDEMA standard
- **Support SMART and TRIM commands**
- **Support Hardware Write Protect function (Optional)**
- **Certification & Compliance**
 - RoHS
 - WHQL

2.2. Device Capacity

Capacity	IDEMA Standard		User Data Size
	512Bytes/Sector	4KBytes/Sector	
	Total Sectors (LBA)	Total Sectors (LBA)	
32GB	62,533,296	7,816,662	Depended on file management
60GB	117,231,408	14,653,926	
64GB	125,045,424	15,630,678	
120GB	234,441,648	29,305,206	
128GB	250,069,680	31,258,710	
240GB	468,862,128	58,607,766	
256GB	500,118,192	62,514,774	
480GB	937,703,088	117,212,886	
512GB	1,000,215,216	125,026,902	
960GB	1,875,385,008	234,423,126	
1TB	2,000,409,264	250,051,158	

Notes:

1. 1 Gigabyte (GB) is equal to 1,000,000,000 Bytes; 1 sector is equal to 512 Bytes.
2. The calculation is following IDEMA Standard.
3. The total actual user data size of the SSD may be less than device capacity due to SSD format, SSD partition, operating system.
EX: OS shows 223.57GB (NTFS) with 240GB SSD.

2.3. Performance

Capacity	Flash Structure	Sequential (MB/s)		4K Random (IOPS)	
		Read	Write	Read	Write
60GB/64GB	64GB x 1, BiCS5 TLC, BGA	380	265	36,500	57,500
120GB/128GB	64GB x 2, BiCS5 TLC, BGA	550	450	44,500	78,500
240GB/256GB	128GB x 2, BiCS5 TLC, BGA	550	485	75,500	82,500
480GB/512GB	256GB x 2, BiCS5 TLC, BGA	550	500	91,500	83,500
960GB/1TB	512GB x 2, BiCS5 TLC, BGA	550	500	96,000	85,500
32GB	64GB x 2, BiCS5 pSLC, BGA	540	465	49,500	78,500
64GB	128GB x 2, BiCS5 pSLC, BGA	550	485	85,500	84,500
128GB	256GB x 2, BiCS5 pSLC, BGA	550	500	96,000	86,000

Notes:

- Performance may differ according to flash configuration and platform.
- The table above is for reference only.
- Performance is measured with the follow conditions
 - CrystalDiskMark 6.0, 1GB range, QD32T1 for sequential
 - IOmeter, QD32T8, 1GB range for 4K Random
 - Windows 10 professional (x64), Version 1809
- Measurement environment: Room temperature: 20~25℃, humidity: 40~60%RH, DC+3.3V condition.

2.4. TBW (TeraBytes Written) and DWPD (Drive Write Per Day)

Capacity	Flash Type	TBW	DWPD
60GB/64GB	TLC	65	0.92
120GB/128GB	TLC	90	0.64
240GB/256GB	TLC	220	0.78
480GB/512GB	TLC	540	0.96
960GB/1TB	TLC	1,080	0.96
32GB	pSLC	1,000	28.53
64GB	pSLC	3,000	42.81
128GB	pSLC	6,400	45.66

Notes:

1. TBW is measured by JEDEC 219A Client workload.
2. TBW may differ according to flash configuration, platform and data written.
3. DWPD is calculated based on 3-year lifetime.
4. $DWPD \text{ (Drive Write Per Day)} = TBW / [365 \times \text{years} \times \text{User Capacity(TB)}]$
5. The endurance of SSD could be estimated based on user behavior, NAND endurance cycles, and write amplification factor. It is not guaranteed by flash vendor.

2.5. POR/SPOR Standby Ready Time

- POR/SPOR Ready Time

Capacity	POR ready time				SPOR ready time			
	Power On		Identify		Power On		Identify	
	Typ.	Max.	Typ.	Max.	Typ.	Max.	Typ.	Max.
60GB/64GB	300	500	350	550	5,000	9,000	5,100	9,100
120GB/128GB					5,000		5,100	
240GB/256GB					8,000		8,100	
480GB/512GB					8,000		8,100	
1920GB/2TB					8,000		8,100	
32GB (pSLC)					5,000		5,100	
64GB (pSLC)					8,000		8,100	
128GB (pSLC)					8,000		8,100	

Unit: ms

Notes:

- POR/SPOR stands for following:
 - POR (Power On Ready): The ready time variation depends on data recover size.
 - SPOR (Power On Ready after Sudden Power Off): The ready time variation depends on data recover size.
- Power On/Identify ready time stands for following:
 - Power on Time: From Power On to SSD response after drive ready.
 - Identify Time: Power on Time + host issue Identify Command, response Ack.
- Measurement environment: Room temperature: 20~25℃, humidity: 40~60%RH, DC+3.3V condition.

2.6. Write Protect Function (Optional)

The write protect function is triggered by slid switch. This used to set the device as a write protection device after power up. When the function is triggered, the data can't be written to the device. The device is then set as read only.



3. ENVIRONMENTAL SPECIFICATIONS



3.1. Environmental Conditions

3.1.1. Temperature Specification

	Mode	Min.	Max.	Unit
Temperature Ranges	Operation (Standard)	0	70	°C
	Operation (Wide)	-40	85	°C
	Storage	-40	85	°C
Humidity (non- condensing)	Operation	5	90	%
	Storage	5	93	%
Temperature Cycle Test	Operation (Standard)	0	70	°C
	Operation (Wide)	-40	85	°C
	Storage	-40	85	°C

Notes:

- The operation temperature means the case temperature, in which can be detected via the S.M.A.R.T. Airflow is suggested and it will allow device to be operated at appropriate temperature for each component during heavy workloads environment.

3.1.2. High Temperature Test Condition

		Temperature	Humidity	Test Time
Operation	Standard Temperature	70°C	0% RH	72 hours
	Wide Temperature	85°C		
Storage	Standard Temperature	85°C	0% RH	168 hours
	Wide Temperature			

Test Reference: IEC 60068-2-2

3.1.3. Low Temperature Test Condition

		Temperature	Humidity	Test Time
Operation	Standard Temperature	0°C	0% RH	72 hours
	Wide Temperature	-40°C		
Storage	Standard Temperature	-40°C	0% RH	168 hours
	Wide Temperature			

Test Reference: IEC 60068-2-1

3.1.4. High Humidity Test Condition

		Temperature	Humidity	Test Time
Operation	Standard Temperature	40°C	90% RH	72 hours
	Wide Temperature	55°C		
Storage	Standard Temperature	40°C	93% RH	96 hours
	Wide Temperature	55°C		

Test Reference: IEC 60068-2-3

3.1.5. Temperature Cycle Test

		Temperature	Humidity	Test Time
Operation	Standard Temperature	0°C	30 min	20 Cycles
		70°C		
	Wide Temperature	-40°C	30 min	20 Cycles
		85°C		
Storage	Standard Temperature	-40°C	30 min	30 Cycles
		85°C		
	Wide Temperature	-40°C	30 min	50 Cycles
		85°C		

Test Reference: IEC 60068-2-14

3.1.6. Mechanical Specification

Items			Condition
Shock	Non-operational	Acceleration Force	1500G 0-p with half sine wave (0.5ms)
Vibration	Non-operational	Frequency/Displacement	20Hz~80Hz/1.52mm
		Frequency/Acceleration	80Hz~2000Hz/20G p-p with sine wave
Drop	Non-operational	Height of Drop	80cm free fall
		Number of Drop	6 face of each unit
		Conflicting Material	Concrete floor

3.1.7. Electrostatic Discharge (ESD)

Specification	± 4KV
EN 55024	± 4KV each 25 times, 1 second for 1 time. - Contact discharge. - Device functions are affected, EUT will be back to normal state.
CISPR 24	
EN 61000-4-2	
IEC 61000-4-2	

3.1.8. EMI Compliance

Specification
CE: EN 55032, CISPR 32
FCC: ANSI C63.4
VCCI: VCCI-CISPR 32
BSMI: CNS 13438

3.2. Package Qualification

3.2.1. High Temperature Storage Life Test (HTSL)

Parameter	Test Condition	
Storage	Temperature	Test Duration
	150°C	168/1000 hours

Test Reference: JESD22 A103

3.2.2. Solderability Test

Parameter	Test Condition
Storage	85°C/85% RH 16 hours, bake 1 hour at 125°C. - Molten solder temperature: 245±5°C - Dwell time: 5 seconds

Note: Spec: > 95% of coating area, pinhole, voids, do not exceed 5% of total area.

3.2.3. Pre-condition Test

Parameter	Test Method	Test Condition
Storage	JESD22-A113	- Temperature Cycle (-65°C/150°C, 5 cycles) - Baking (125°C, 24 hours) - Temp & Humidity Soaking (30°C/60% RH, 192 hours) - IR Reflow 3 cycles

Note: The parts passing this test will be used to do HAST and TCT.

3.2.4. High Acceleration Stress Test (HAST/unbias)

Parameter	Test Method	Test Condition		
		Ambient Temperature	Ambient Humidity	Test Duration
Storage	JESD22-A110	130°C	85% RH	96 hours

3.2.5. Temperature Cycling Test (TCT)

Parameter	Test Method	Test Condition		
		High Temperature	Low Humidity	Test Duration
Storage	JESD22-A104	150°C	-65% RH	200/500 cycles

3.3. UBER

Capacity	UBER
32GB ~ 1TB	< 1 sector per 10^{16} bits read

Notes:

1. UBER (Uncorrectable Bit Error Rates) means the uncorrectable error per bits read.
2. $UBER = FER \text{ (fail rate)} / \text{Data Size (user data bit)}$.
3. $FER = \text{uncorrectable ECC frame number} / \text{total ECC frame number}$.
4. The LDPC capability > 120bit/KB.

3.4. MTBF

MTBF, an acronym for Mean Time between Failures, is a measure of reliability of a device. Its value represents the average time between a repair and the next failure. The unit of MTBF is in hours. The higher the MTBF value, the higher the reliability of the device.

Our MTBF result is based on simulation software (Relex 7.3). Please note that a lower MTBF should be expected for higher capacity drives, and we apply the lowest MTBF for all capacities.

Capacity	MTBF
32GB ~ 1TB	> 3 million hours

4. ELECTRICAL SPECIFICATIONS



4.1. Supply Voltage

Parameter	Rating
Operating Voltage	3.3V $\pm$ 5%
Rise Time (Max/Min)	100ms / 0.1ms
Fall Time (Max/Min)	5s / 10ms
Min. off Time	1s

Notes:

1. Minimum time between power removed from SSD ($V_{cc} < 100$ mV) and power re-applied to the drive.
2. Ensure the voltage of each power domain in SSD has enough time to discharge less than 0.1V.
3. Rise Time during from 10% to 90% of 3.3V.
4. Fall Time during from 90% to 10% of 3.3V.

4.2. Power Consumption

Capacity	Flash Structure	Read	Write	Partial	Slumber	Idle
64GB	64GB x 1, BiCS5 TLC, BGA	850	750	50	15	180
128GB	64GB x 2, BiCS5 TLC, BGA	1,000	1,100	50	15	180
256GB	128GB x 2, BiCS5 TLC, BGA	1,050	1,250	50	18	180
512GB	256GB x 2, BiCS5 TLC, BGA	1,100	1,350	50	18	180
1TB	512GB x 2, BiCS5 TLC, BGA	1,150	1,400	50	18	180
32GB	64GB x 2, BiCS5 pSLC, BGA	1,150	1,150	65	25	175
64GB	128GB x 2, BiCS5 pSLC, BGA	1,150	1,150	65	25	175
128GB	256GB x 2, BiCS5 pSLC, BGA	1,250	1,200	65	25	175

Unit: mW

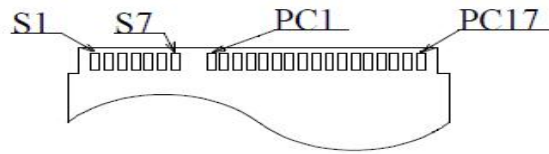
Notes:

1. It's average value of power consumption is achieved based on 100% conversion efficiency.
2. Sequential R/W is measured while testing 4000MB sequential R/W 5 times by CrystalDiskMark.
3. Power Consumption may differ according to flash configuration and platform.
4. Measurement environment: Room temperature: 20~25°C, humidity: 40~60%RH, DC+3.3V condition.

5. INTERFACE



5.1. Pin Assignment and Descriptions



Pin #	Segment	Pin Definition	Type	Description	Meting Sequence
S1	SATA	SGND	Signal GND	Ground for signal integrity	1 st
S2	SATA	A+	SATA Differential	Signal Pair A	2 nd
S3	SATA	A-	SATA Differential	Signal Pair A	2 nd
S4	SATA	SGND	Signal GND	Ground for signal integrity	1 st
S5	SATA	B-	SATA Differential	Signal Pair B	2 nd
S6	SATA	B+	SATA Differential	Signal Pair B	2 nd
S7	SATA	SGND	Signal GND	Ground for signal integrity	1 st
	Key				
	Key				
PC1	PWR/CTL	CDI	Input	Card Detect In	3 rd
PC2	PWR/CTL	PGND	Device GND		1 st
PC3	PWR/CTL	DEVSLP	DEVSLP Card Input	DevSleep Power State Enable	2 nd
PC4	PWR/CTL			Reserved	2 nd
PC5	PWR/CTL			Reserved	2 nd
PC6	PWR/CTL			Reserved	2 nd
PC7	PWR/CTL	PGND	Device GND		1 st
PC8	PWR/CTL	LED1	LED Output	LED Output	2 nd
PC9	PWR/CTL	LED2	LED Output	LED Output	2 nd
PC10	PWR/CTL			Reserved	2 nd
PC11	PWR/CTL			Reserved	2 nd
PC12	PWR/CTL	IFDet	GND	Card output, connect to PGND on card	2 nd
PC13	PWR/CTL	PWR	3.3V	Device Power (3.3V)	2 nd
PC14	PWR/CTL	PWR	3.3V	Device Power (3.3V)	2 nd
PC15	PWR/CTL	PGND	Device GND	Device Ground	1 st
PC16	PWR/CTL	PGND	Device GND	Device Ground	1 st
PC17	PWR/CTL	CDO	Output	Card Detect Out	3 rd

6. SUPPORTED COMMANDS



6.1. ATA Command List

Op-Code	Command Description	Op-Code	Command Description
00h	NOP	60h	Read FPDMA Queued
06h	Data Set Management	61h	Write FPDMA Queued
10h	Recalibrate	70h	Seek
20h	Read Sectors	90h	Execute Device Diagnostic
21h	Read Sectors without Retry	91h	Initialize Device Parameters
24h	Read Sectors EXT	92h	Download Microcode
25h	Read DMA EXT	93h	Download Microcode DMA
27h	Read Native Max Address EXT	B0h	SMART
29h	Read Multiple EXT	B0h	D0h SMART READ DATA
2Fh	Read Log EXT	B0h	D1h SMART READ DATA ATTRIBUTE THRESHOLD
30h	Write Sectors	B0h	D2h SMART ENABLE/DISABLE ATTRIBUTE AUTOSAVE
31h	Write Sectors without Retry	B0h	D3h SMART SAVE ATTRIBUTE VALUES
34h	Write Sectors EXT	B0h	D4h SMART EXECUTE OFF-LINE IMMEDIATE
35h	Write DMA EXT	B0h	D5h SMART READ LOG
37h	Set Native Max Address EXT	B0h	D6h SMART WRITE LOG
39h	Write Multiple EXT	B0h	D8h SMART ENABLE OPERATIONS
3Dh	Write DMA FUA EXT	B0h	D9h SMART DISABLE OPERATIONS
3Fh	Write Long EXT	B0h	DAh SMART RETURN STATUS
40h	Read Verify Sectors	B0h	DBh SMART ENABLE/DISABLE AUTOMATIC OFF-LINE
41h	Read Verify Sectors without Retry	B1h	DEVICE CONFIGURATION OVERLAY
42h	Read Verify Sectors EXT	B1h	C0h DEVICE CONFIGURATION RESTORE
45h	Write Uncorrectable EXT	B1h	C1h DEVICE CONFIGURATION FREEZE LOCK
47h	Read Log DMA EXT	B1h	C2h DEVICE CONFIGURATION IDENTIFY
57h	Write Log DMA EXT	B1h	C3h DEVICE CONFIGURATION SET
B1h	C4h DEVICE CONFIGURATION IDENTIFY DMA	ECh	Identify Device
B1h	C5h DEVICE CONFIGURATION SET DMA	EFh	Set Features
C4h	Read Multiple	EFh	02h Enable 8-bit PIO transfer mode
Op-Code	Command Description	Op-Code	Command Description

C5h	Write Multiple	EFh	03h		Set transfer mode based on value in Count field
C6h	Set Multiple Mode	EFh	05h		Enable advanced power management
C8h	Read DMA	EFh	10h		Enable use of Serial ATA feature
C9h	Read DMA without Retry	EFh	10h	02h	Enable DMA Setup FIS Auto-Activate optimization
CAh	Write DMA	EFh	10h	03h	Enable Device-initiated interface power state (DIPM) transitions
CBh	Write DMA without Retry	EFh	10h	06h	Enable Software Settings Preservation (SSP)
CEh	Write Multiple FUA EXT	EFh	10h	07h	Enable Device Automatic Partial to Slumber transitions
E0h	Standby Immediate	EFh	10h	09h	Enable Device Sleep
E1h	Idle Immediate	EFh	55h		Disable read look-ahead feature
E2h	Standby	EFh	66h		Disable reverting to power-on defaults
E3h	Idle	EFh	82h		Disable write cache
E4h	Read Buffer	EFh	85h		Disable advanced power management
E5h	Check Power Mode	EFh	90h		Disable use of Serial ATA feature set
E6h	Sleep	EFh	90h	02h	Disable DMA Setup FIS Auto-Activate optimization
E7h	Flush Cache	EFh	90h	03h	Disable Device-initiated interface power state (DIPM) transitions
E8h	Write Buffer	EFh	90h	06h	Disable Software Settings Preservation (SSP)
E9h	Read Buffer DMA	EFh	90h	07h	Disable Device Automatic Partial to Slumber transitions
EAh	Flush Cache EXT	EFh	90h	09h	Disable Device Sleep
EBh	Write Buffer DMA	EFh	AAh		Enable read look-ahead feature
EFh	CCh	Enable reverting to power-on defaults		F4h	Security Erase Unit
F1h	Security Set Password		F5h	Security Freeze Lock	
F2h	Security Unlock		F6h	Security Disable Password	
F3h	Security Erase Prepare		F8h	Read Native Max Address	

6.2. Identify Device Data

The following table details the sector data returned by the IDENTIFY DEVICE command.

Word	F: Fixed V: Variable X: retired/obsolete /reserved	Default Value	Description
0	F	0040h	General configuration bit-significant information
1	X	*1	Obsolete – Number of logical cylinders
2	F	C837h	Specific configuration
3	X	0010h	Obsolete – Number of logical heads (16)
4-5	X	00000000h	Retired
6	X	003Fh	Obsolete – Number of logical sectors per logical track (63)
7-8	X	00000000h	Reserved for assignment by the Compact Flash Association
9	X	0000h	Retired
10-19	V	Varies	Serial number (20 ASCII characters)
20-21	X	0000h	Retired
22	X	0000h	Obsolete
23-26	V	Varies	Firmware revision (8 ASCII characters)
27-46	V	Varies	Model number (xxxxxxx)
47	F	8010h	7:0- Maximum number of sectors transferred per interrupt on MULTIPLE commands
48	F	4000h	Reserved
49	F	2F00h	Capabilities
50	F	4000h	Capabilities
51-52	X	00000000h	Obsolete
53	F	0007h	Words 88 and 70:64 valid
54	X	*1	Obsolete – Number of logical cylinders
55	X	0010h	Obsolete – Number of logical heads (16)
56	X	003Fh	Obsolete – Number of logical sectors per track (63)
57-58	X	*2	Obsolete – Current capacity in sectors
59	F	0110h	Number of sectors transferred per interrupt on MULTIPLE commands
60-61	V	*3	Maximum number of sector (28bit LBA mode)
Word	F: Fixed	Default Value	Description

	V: Variable X: retired/obsolete /reserved		
62	X	0000h	Obsolete
63	F	0407h	Multi-word DMA modes supported/selected
64	F	0003h	PIO modes supported
65	F	0078h	Minimum Multiword DMA transfer cycle time per word
66	F	0078h	Manufacturer's recommended Multiword DMA transfer cycle time
67	F	0078h	Minimum PIO transfer cycle time without flow control
68	F	0078h	Minimum PIO transfer cycle time with IORDY flow control
69	F	1F00h	Additional Supported
70	X	0000h	Reserved
71-74	X	0h	Reserved for the IDENTIFY PACKET DEVICE command
75	F	001Fh	Queue depth
76	F	C50Eh	Serial SATA capabilities
77	F	0006h	Supported Serial ATA Phy speed
78	F	044Ch	Serial ATA features supported
79	F	0040h	Serial ATA features enabled
80	F	0FF8h	Major Version Number
81	F	0000h	Minor Version Number
82	F	746Bh	Command set supported
83	F	7D09h	Command set supported
84	F	4163h	Command set/feature supported extension
85	F	7469h	Command set/feature supported or enabled
86	F	BC01h	Command set/feature supported or enabled
87	F	4163h	Command set/feature supported or enabled
88	F	007Fh	Ultra DMA Modes
89	F	000Ah	Time required for Normal Erase mode SECURITY ERASE UNIT command
90	F	001Eh	Time required for an Enhanced Erase mode SECURITY ERASE UNIT command
91	F	0000h	Current advanced power management value
92	F	FFFEh	Master Password Revision Code
Word	F: Fixed V: Variable	Default Value	Description

	X: retired/obsolete /reserved		
93	F	0000h	Hardware reset result. The contents of the bits (12:0) of this word can be changed only during the execution of hardware reset.
94	X	0000h	Vendor's recommended and actual acoustic management value
95	F	0000h	Stream Minimum Request Size
96	F	0000h	Streaming Transfer Time – DMA
97	F	0000h	Streaming Access Latency – DMA and PIO
98-99	F	00000000h	Streaming Performance Granularity
100-103	V	*4	Maximum user LBA for 48 bit Address feature set
104	F	0000h	Streaming Transfer Time – PIO
105	F	0004h	Maximum number of 512-byte blocks per DATA SET MANAGEMENT command
106	F	4000h	Physical sector size/Logical sector size
107	F	0000h	Inter-seek delay for ISO-7779 acoustic testing in microseconds
108-111	F	Varies	Reserved
112-115	X	0h	Reserved
116	X	0000h	Reserved
117-118	F	00000000h	Words per logical Sector
119	F	4018h	Supported settings
120	F	4018h	Command set/Feature Enabled/Supported
121-126	X	0h	Reserved
127	X	0000h	Obsolete
128	F	0021h	Security status
129-159	V	Varies	Vendor specific
160	X	0000h	Compact Flash Association (CFA) power mode 1
161-167	X	0h	Reserved for assignment by the CFA
168	V	Varies	Device Nominal Form Factor
169	F	0001h	DATA SET MANAGEMENT command is supported
170-173	F	0h	Additional Product Identifier
174-175	X	0h	Reserve
Word	F: Fixed V: Variable X:	Default Value	Description

	retired/obsolete /reserved		
176-205	F	0h	Current media serial number
206	F	0000h	SCT Command Transport(
207-208	X	00000000h	Reserved
209	F	4000h	Alignment of logical blocks within a physical block
210-211	F	0000h	Write-Read-Verify Sector Count Mode 3 (not support)
212-213	F	0000h	Write-Read-Verify Sector Count Mode 2 (not support)
214-216	X	0000h	NV Cache relate (not support)
217	F	0001h	Non-rotating media device
218	X	0000h	Reserved
219	X	0000h	NV Cache relate (not support)
220	V	0000h	Write read verify feature set current mode
221	X	0000h	Reserved
222	F	107Fh	Transport major version number
223	F	0000h	Transport minor version number
224-229	X	0h	reserved
230-233	F	0h	Extend number of user addressable sectors
234	F	0001h	Minimum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
235	F	FFFEh	Maximum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h
236-242	X	0h	Reserved
243	X	0000h	Reserved
244-254	X	0h	Reserved
255	F	XXA5h XX is variable	Integrity word (Checksum and Signature)

▪ **List of Device Identification for Each Capacity**

Capacity (GB)	*1 (Word 1/Word 54)	*2 (Word 57–58)	*3 (Word 60–61)	*4 (Word 100–103)
32	3FFFh	FBFC10h	3BA2EB0h	3BA2EB0h
60	3FFFh	FBFC10h	6FCCF30h	6FCCF30h
64	3FFFh	FBFC10h	7740AB0h	7740AB0h
120	3FFFh	FBFC10h	DF94BB0h	DF94BB0h
128	3FFFh	FBFC10h	EE7C2B0h	EE7C2B0h
240	3FFFh	FBFC10h	0FFFFFFFh	1BF244B0h
256	3FFFh	FBFC10h	0FFFFFFFh	1DCF32B0h
480	3FFFh	FBFC10h	0FFFFFFFh	37E436B0
512	3FFFh	FBFC10h	0FFFFFFFh	3B9E12B0h
960	3FFFh	FBFC10h	0FFFFFFFh	6FC81AB0h
1024	3FFFh	FBFC10h	0FFFFFFFh	773BD2B0h

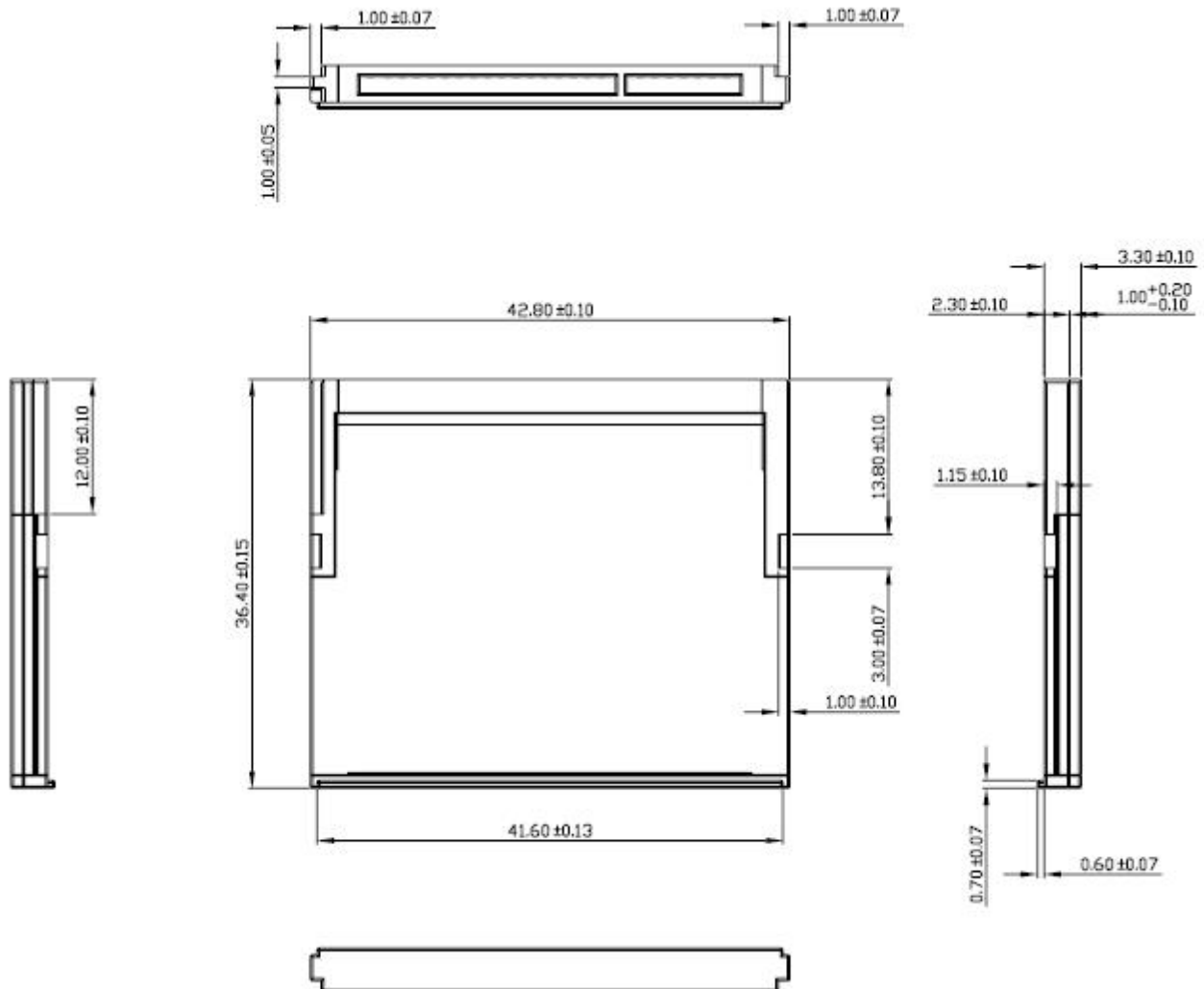
6.3. S.M.A.R.T. Attributes

Entry	ID	Description
0	0x01	Number of Uncorrectable Errors Accumulated.
1	0x09	Power on Hours Count.
2	0x0C	Power Cycle Count (number of power on/off cycles accumulated)
		SATA PHY Error Count
		(Only record from power on, when power off this value will clear to zero.
3	0xA8	These values include all PHY error count, ex data FIS CRC, code error, disparity error, command FIS CRC.....)
4	0xAA	Bad Block Count (early bad count and later bad count)
5	0xAD	Erase Count (max. erase count and average erase count)
6	0xC0	Unexpected Power Loss Count
7	0xC2	Temperature (show 33°C if no thermal sensor)
8	0xDA	Number of Accumulation CRC Error (read/write data FIS CRC error)
9	0xE7	SSD Life Remaining
10	0xF1	Host Write (GB)

7. PHYSICAL DIMENSION



CFast Type I: 36.4mm (L) x 42.8mm (W) x 3.3mm (H)



8. TERMINOLOGY



The following table is to list out the acronyms that have been applied throughout the document.

Term	Definitions
ATTO	Commercial performance benchmark application
DDR	Double data rate (SDRAM)
DIPM	Device initiated power management
HIPM	Host initiated power management
LBA	Logical block addressing
MB	Mega-byte
MTBF	Mean time between failures
NCQ	Native command queue
SATA	Serial advanced technology attachment
S.M.A.R.T.	Self-monitoring, analysis and reporting technology
SSD	Solid state disk